

OBSOLETE PRODUCT
POSSIBLE SUBSTITUTE PRODUCT
HI-5043

March 20<u>00</u>

File Number

er 3130.3

# **Dual SPDT CMOS Analog Switch**

The IH5043 analog switch uses an improved, high voltage CMOS monolithic technology. These devices provide ease of use and performance advantages not previously available from solid state switches.

Key performance advantage is TTL compatibility and ultra low power operation. The quiescent current requirement is less than 1mA. Also, the IH5043 guarantees Break-Before-Make switching, accomplished by extending the t<sub>ON</sub> time (300ns Typ), so that it exceeds t<sub>OFF</sub> time (200ns Typ). This insures that an ON channel will be turned OFF before an OFF channel can turn ON. The need for external logic required to avoid channel to channel shorting during switching is eliminated.

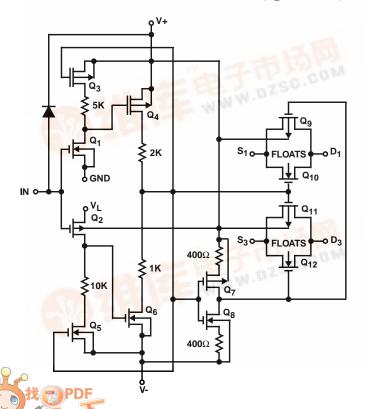
#### Part Number Information

PART NUMBER	TEMP. RANGE (°C)	PACKAGE	PKG. NO.
IH5043CPE	0 to 70	16 Ld PDIP	E16.3
IH5043CY	0 to 70	16 Ld SOIC	M16.15

## Schematic Diagram

.dzsc.com

FUNCTIONAL DRIVER, TYPICAL DRIVER, GATE (1/2 AS SHOWN)



#### **Features**

- See HI504X for Other Functions
- Dual SPDT

**Pinout** 

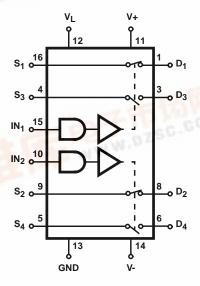
- Switches Greater than 20V<sub>P-P</sub> Signals with ±15V Supplies
- Quiescent Current Less than 1mA
- Break-Before-Make Switching t<sub>OFF</sub> 200ns, t<sub>ON</sub> 300ns (Typ)
- TTL, DTL, CMOS, PMOS Compatible

#### IH5043 (PDIP, SOIC) TOP VIEW 16 S<sub>1</sub> D<sub>1</sub> 1 15 IN<sub>1</sub> NC 2 14 V- $D_3$ 13 GND $S_3$ 12 V<sub>L</sub> S<sub>4</sub> 11 V+ D<sub>4</sub> 6 10 IN<sub>2</sub> NC 7

9 S<sub>2</sub>

# Functional Diagram

D<sub>2</sub> 8



SWITCH STATES SHOWN ARE FOR LOGIC "1" INPUT

#### TRUTH TABLE

LOGIC	SWITCH 1, 2	SWITCH 3, 4		
0	Off	On		
1	On	Off		

## IH5043

## **Absolute Maximum Ratings**

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## **Thermal Information**

Thermal Resistance (Typical, Note 1)	$\theta_{JA}$ ( $^{o}C/W$ )
PDIP Package	90
SOIC Package	
Maximum Junction Temperature (Plastic Packages)	150°C
Maximum Storage Temperature65	<sup>o</sup> C to 150 <sup>o</sup> C
Maximum Lead Temperature (Soldering 10s) (SOIC - Lead Tips Only)	
(,	

# **Operating Conditions**

Temperature Range . . . . . . . . . . . . . . . . 0 °C to 70 °C

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

#### NOTE:

1.  $\theta_{JA}$  is measured with the component mounted on an evaluation PC board in free air.

## **Electrical Specifications** V+ = +15V, V- = -15V, $V_L = +5V$

	TEST CONDITIONS		(NOTES 2, 3)		
PER CHANNEL PARAMETER			25°C	70°C	UNITS
DYNAMIC CHARACTERISTICS					
Turn ON Time, t <sub>ON</sub>	$R_L = 1k\Omega$ , $V_{ANALOG} = -10V$ to +10V, See Figure 6	-	1000	-	ns
Turn OFF Time, t <sub>OFF</sub>		-	500	-	ns
Charge Injection, Q	See Figure 7	-	20 (Typ)	-	mV
OFF Isolation, OIRR	$f = 1MHz$ , $R_L = 100\Omega$ , $C_L \le 5pF$ , See Figure 4	-	50 (Typ)	-	dB
Crosstalk, CCRR	One Channel Off; Any Other Channel Switches as per Figure 3	-	-50 (Typ)	-	dB
DIGITAL INPUT CHARACTERISTICS					
Input Logic Current, I <sub>IN(ON)</sub>	V <sub>IN</sub> = 2.4V	±1	±1	10	μА
Input Logic Current, I <sub>IN(OFF)</sub>	V <sub>IN</sub> = 0.8V	±1	±1	10	μА
ANALOG SWITCH CHARACTERISTICS					
Drain-Source ON Resistance, r <sub>DS(ON)</sub>	I <sub>S</sub> = 10mA, V <sub>ANALOG</sub> = -10V to +10V	80	80	130	Ω
Channel-to-Channel r <sub>DS(ON)</sub> Match, ∆r <sub>DS(ON)</sub>		-	30 (Typ)	-	Ω
Minimum Analog Signal Handling Capability, V <sub>ANALOG</sub>		-	±10 (Typ)	-	V
Switch OFF Leakage Current, I <sub>D(OFF)</sub> , I <sub>S(OFF)</sub>	V <sub>ANALOG</sub> = -10V to +10V	-	±5	100	nA
Switch ON Leakage Current, I <sub>D(ON)</sub> +I <sub>S(ON)</sub>	$V_D = V_S = -10V \text{ to } +10V$	-	±10	100	nA
POWER SUPPLY CHARACTERISTICS					
+ Power Supply Quiescent Current, I+		10	10	100	μА
- Power Supply Quiescent Current, I-		10	10	100	μА
+5V Supply Quiescent Current, IL		10	10	100	μА
Ground Quiescent Current, I <sub>GND</sub>		10	10	100	μА

## NOTES:

- 2. Typical values are for design aid only, not guaranteed and not subject to production testing.
- 3. Min or Max value unless otherwise specified.

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## Test Circuits and Waveforms

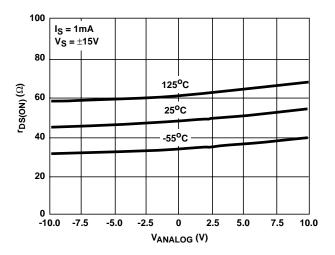


FIGURE 1.  $r_{DS(ON)}$  vs analog input voltage

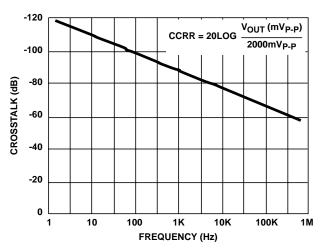


FIGURE 3A. CROSSTALK vs FREQUENCY

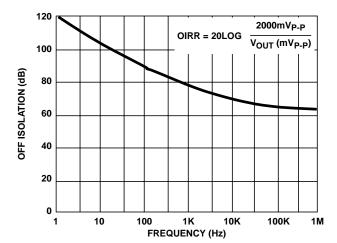


FIGURE 4A. OFF ISOLATION vs FREQUENCY

160 I<sub>S</sub> = 1mA 140 120  $V_S = \pm 10V$ r<sub>DS(ON)</sub> (Ω) 80 80  $V_S = \pm 12V$ V<sub>S</sub> = ±15V 60 40 20 0 -10.0 -7.5 2.5 5.0 7.5 10.0 -5.0 V<sub>ANALOG</sub> (V)

FIGURE 2.  $r_{DS(ON)}$  vs POWER SUPPLY VOLTAGE

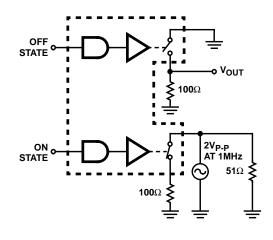


FIGURE 3B. TEST CIRCUIT

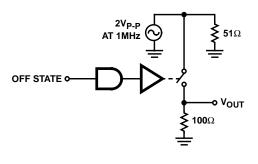


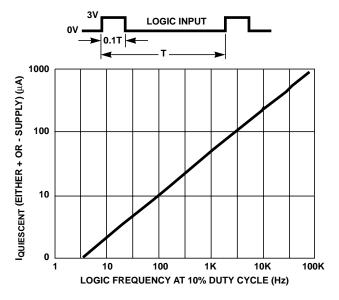
FIGURE 4B. TEST CIRCUIT

FIGURE 4. OFF ISOLATION

FIGURE 3. CROSSTALK

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# Test Circuits and Waveforms (Continued)



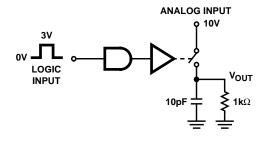
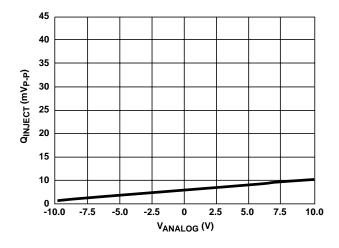


FIGURE 5. SUPPLY CURRENT vs LOGIC FREQUENCY

FIGURE 6.  $t_{\mbox{ON}}$  AND  $t_{\mbox{OFF}}$  TEST CIRCUIT



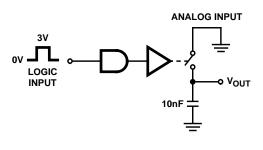


FIGURE 7A. CHARGE INJECTION vs ANALOG INPUT VOLTAGE
FIGURE 7. CHARGE INJECTION

FIGURE 7B. TEST CIRCUIT

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# **Typical Applications**

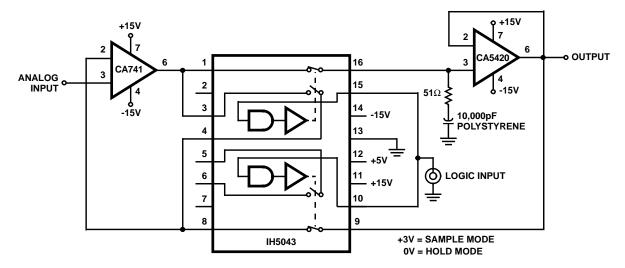


FIGURE 8. IMPROVED SAMPLE AND HOLD

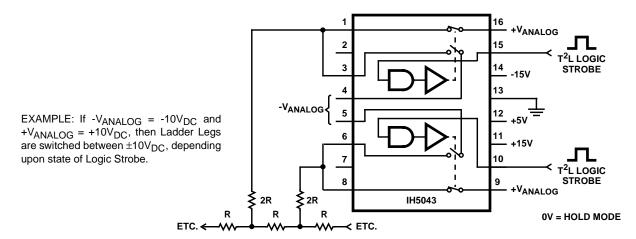


FIGURE 9. USING THE CMOS SWITCH TO DRIVE AN R/2R LADDER NETWORK (2 LEGS)

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# Typical Applications (Continued)

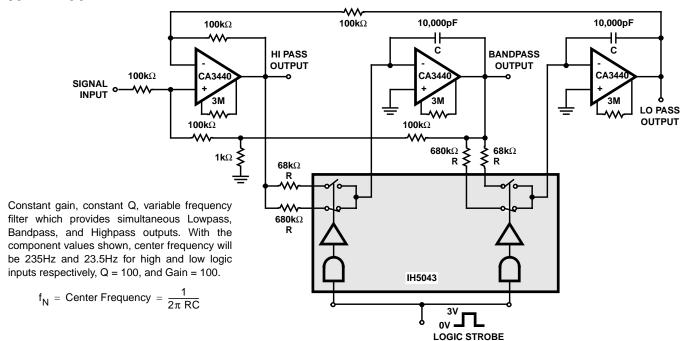


FIGURE 10. DIGITALLY TUNED LOW POWER ACTIVE FILTER

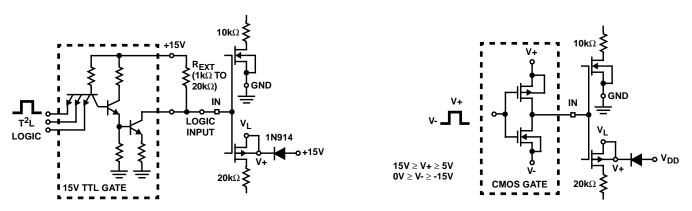


FIGURE 11. INTERFACING WITH TTL OPEN COLLECTOR LOGIC (TYP EXAMPLE FOR +15V CASE SHOWN)

FIGURE 12. INTERFACING WITH CMOS LOGIC

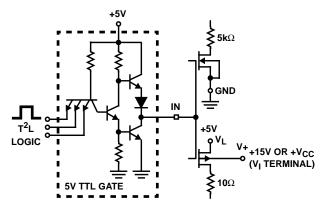


FIGURE 13. TTL LOGIC INTERFACE

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## IH5043

## Die Characteristics

**DIE DIMENSIONS:** 

1778μm x 1905μm

**METALLIZATION:** 

Type: Al

Thickness: 10kÅ ±1kÅ

## **PASSIVATION:**

Type: PSG/Nitride

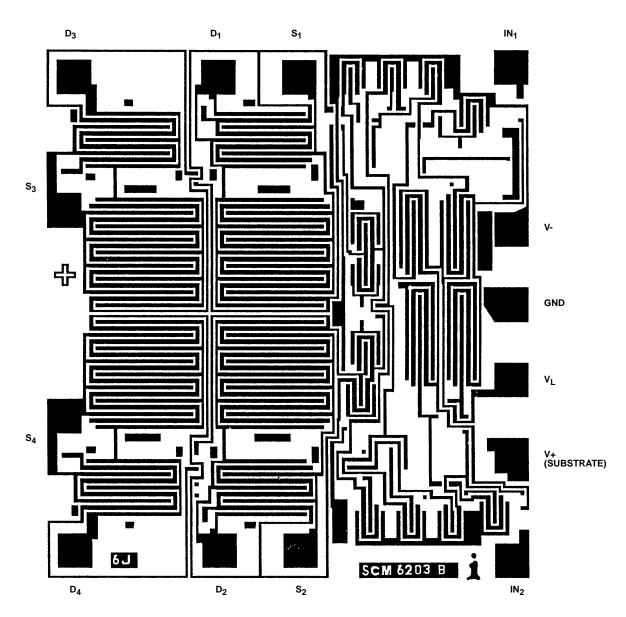
PSG Thickness: 7kÅ ±1.4kÅ Nitride Thickness: 8kÅ ±1.2kÅ

# **WORST CASE CURRENT DENSITY:**

 $9.1 \times 10^4 \text{ A/cm}^2$ 

# Metallization Mask Layout

IH5043



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